Messrs.

Change Notice of the Plating Type for M1F Package Products

Dear Valued Customer,

We hereby inform you of the change of the plating type for the captioned devices. Please see below for the details:

<Products concerned>

1) M1F602) M1F60T3) M1FE404) M1FS45) M1FS66) M1FL20U7) M1FL408) M1FP39) M1F8010) M1FM311) M1FH312) M1FJ4

<Content of Change>

The Pb free plating of electrode terminals shall be unified to Sn plating from Sn-Cu or Sn-Pb. In accordance with the unification, the spec code will be altered from 50x3 or 4063 to 60x3.

<Reason of Change>

In order to improve productivity of M1F products by unifying the Pb free plating types.

<Implementation>

The switch shall be made gradually from September, 2006. You are kindly requested to complete the switch by the end of March, 2007.

< Electrical Characteristics>

Equivalent to those of Sn-Cu dipped products.

<Reliability>

Equivalent to those of Sn-Cu dipped products.

<Evaluation of the plating>

Evaluation tests made are equivalent to those for Sn-Cu dipped products. Please see "Technical Data: Evaluation of M1F Sn Plated Products" for the details.

If you have any questions, please do not hesitate to contact us.

Shindengen Electric Mfg. Co., Ltd.

n. Sasaki

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Exhibit

Changes related to the transition to Sn plating

1) The spec code shall be 60x3. (Reference: Sn-Cu dip 50x3, Sn-Pb dip 4063)

2) Marking: Two dots are marked at upper and lower positions at the tail of the date code. (Reference: For Sn-Cu dipped products, one dot is marked at lower position)



Fig-1 Marking of Sn plating



Fig-2 Marking of Sn-Cu dip (Reference)

Technical Data

Evaluation of M1F Sn plated products

- 1. Solderability
- 2. Solder joint reliability
- 3. Whisker
- 4. Recommended soldering conditions
- 5. Reliability Tests

QUALITY ASSURANCE DEPT. ELECTRIC DEVICE DIV.GROUP SHINDENGEN ELECTRIC MFG. CO., LTD.

Revised : Apr 14, 2006

- 1. Evaluation of Solderability by wetting balance method
 - (1)Conditions

Temperature of solder bath: 245 to 255 Type of solder: S n 3A g 0.5Cu Preconditioning: 105 ,100%RH,8h Testing Method: Wetting balance method (Measurement of zero-cross time) Dipping speed: 2mm/s Dipping depth: 0.5mm

(2) Evaluation Result



Notice: Above data is a reference value in which the characteristic of a typical is shown, and no guarantee value.

2. Solder joint reliability

(1) Conditions







Notice: Above data is a reference value in which the characteristic of a typical is shown, and no guarantee value.

n=11

3.Whisker

(1) Condition (No.of samples:n = 5)

Room temperature test: 2000h

Constant temperature/humidity test: 55 /85%, 1000h

Temperature cycle test: -40 to 85 , 1500cy

(2) Result

The result which observed the terminal surface by SEM is shown.

Room temperature test: 2000h



Generating of a whisker is not seen.

Constant temperature/humidity test: 55 /85%, 1000h



Generating of a whisker is not seen.

Temperature cycle test: -40 to 85 , 1500cy



Though Whisker (inside) of about $10\,\mu$ m was observed no further growth of the whisker was identified during its continued test, and there should not be a problem in actual use.

Notice: Above results of whisker evaluation of a terminal are reference data.

4.Recommended soldering conditions

4.1 Infrared-ray reflow conditions



Preheating temperature and time	150	to 180 , 90 ± 3	30s
Heating temperature and time	230	30 ± 10s	
Peak temperature	250	, 10s or less M	ax255
Number of times	2		

4.2 Wavesolder conditions

Solder temperature: 260 ± 5 Heating time: $10 \pm 1s$ Number of times: 1

4.3 Hand solder conditions

Temperature of soldering iron	Heating time	Number of times
MAX 350	MAX 3s	1

5.Reliability tests

5.1 Resistance to soldering heat test

(1) Infrared ray reflow

Peak Temperatu	ire	250	XAM C
Heating	230	30 ±	10s
Preheating	150 ~	180	90 ± 30s
Number of time	S	2	

(2) Flow

Solder temperature	260 ± 5
Heating time	10s
Number of times	1

(3) Result

Infrared-ray reflow	Wavesoldering
0/22	0/22

5.2 Temperature cycle test

Test Conditions: -55 Min 30min <-> RT 5min <-> + 150 Max 30min

Test time 100cy

Result

Infrared-ray reflow	Temperature	c Wavesoldering	Temperature cycle test
0/22			0/22

5.3 Moisture resistance test

Test Conditions Ta= 85 ± 2 RH= $85 \pm 5\%$

Test time 1000h

Result

Infrared-ray reflow Moisture	Wavesoldering	Moisture resistance test
resistance test		
0/22		0/22

Notice: Above results of temperature cycle test and moisture resistance test are reference data.